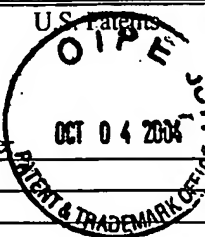


FORM PTO-1449 (MODIFIED)	ATTY. DOCKET NO. 905900-290	SERIAL NO. 10/715,870
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANT: George BORSHUKOV	
	FILING DATE: November 17, 2003	GROUP: 2125

Reference Designation

U.S. Patents



Examiner Initial	Document Number	Date	Name	Class	Filing Date Subclass if appropriate
ELS	AA 6,044,180	03/28/00	Brandestini et al.		
	AB 6,148,113	11/14/00	Wolverton et al.		
	AC 6,166,744	12/26/00	Jaszlics et al.		
	AD 6,124,864	09/26/00	Madden et al.		
	AE 6,160,907	12/12/00	Robotham et al.		
	AF 6,538,396	03/25/03	Vlahos et al.		
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OTHER ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

ELS	AV "Spectral Reflectance, BRDF, Hyperspectral Imaging, Thermal Coatings, FTIRs etc.	Surface Optics Corporation; pages 1-7; www.surfaceoptics.com ;
	AW "A Survey of BRDF Representation for Computer Graphics" by Szymon Rusinkiewicz	CS348, Winter 1997; pages 1-14); www.cs.princeton.edu/smr/cs348c-97/surveyspaper.html
	AX "An Architecture for Accelerated Anisotropic Shading" by Stephen Ehmann	Thesis Submitted for B.S. Degree at University of Toronto; Supervisor, M. Van De Panne, April 1998 Division of Engineering Science
	AY "A Data-Driven Reflectance Model" by Wojciech Matusik et al.	
ELS	AZ "Acquiring Parameters for Rendering" by Zack Waters	Realistic Raytracing; pages 1 - 11; www.cs.wpi.edu/emmanuel/courses/cs563/write_up/s/zackw_measurement

EXAMINER

[Signature]

DATE CONSIDERED

02 / 22 / 06

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.